



GEMaC

Groupe d'Étude de la Matière Condensée

PROFILOMETER

Profilometer DEKTAK 8 (Bruker).

Purchase year 2006.

The contact profilometer DEKTAK 8 is mainly used to perform 2D measurements (thin film thickness, step height for processed samples, SIMS crater depth,...)

It is also possible to obtain 3D maps of the sample surface to measure or control the roughness.

Key elements:

3 vertical measurement ranges: $\pm 3.25 \mu\text{m}$ / $\pm 32 \mu\text{m}$ / $\pm 130 \mu\text{m}$

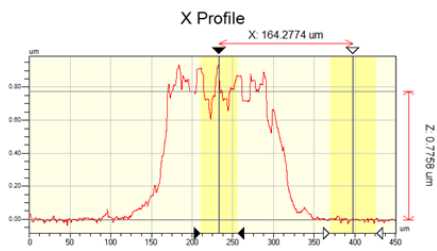
Vertical resolution: 0.1 nm in the range $\pm 3,25 \mu\text{m}$

Scan length: 50 μm to 100 mm

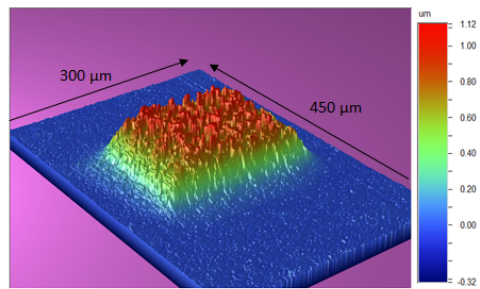
Available styluses: 0.2 μm / 2.5 μm / 12.5 μm of tip radius of curvature

Applied force: 0.03 to 15 mg

Internal use only.



Mesure de la hauteur de marche d'un dépôt métallique réalisé sur un échantillon plan poli



Etude des tous premiers stades de la croissance d'une île flottante obtenue selon les principes de la cuisine moléculaire